	1 A 41 42 11	
Notice of Allowability	Application No.	Applicant(s)
	10/629,130	TAQUCHI, TOMOAKI
	Examiner	Art Unit
	Ernest F. Karlsen	2829
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.		
1. X This communication is responsive to the filing of July 29, 2003.		
2. 🔀 The allowed claim(s) is/are <u>1-12</u> .		
3. 🛮 The drawings filed on 20 February 2004 are accepted by the Examiner.		
4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)		
Attachment(s)	TOK THE BEFOSH OF BIOLOGIC.	AL IVIAT ENIAL.
1. ☑ Notice of References Cited (PTO-892)	5. Notice of Informal P	Patent Application (PTO-152)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Summary Paper No./Mail Dat	
 Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date 	08), 7. Examiner's Amendr	ment/Comment
4. Examiner's Comment Regarding Requirement for Deposit		ent of Reasons for Allowance
of Biological Material	9. Other	7/
	Eml	I Karsen
	E Pi	ERNEST KARLSEN RIMARY EXAMINER

Application/Control Number: 10/629,130 Page 2

Art Unit: 2829

Reasons for Allowance

No reference was found anticipating or a combination of references found making obvious an apparatus for inspecting an array substrate having gate lines, data lines that cross the gate lines, switching elements where the gate and data lines cross, pixel electrodes connected to the switching elements, storage capacitors formed by storage capacitor lines facing a part of each pixel electrode and gate-electrode capacitors formed between the gate lines and the pixel electrodes comprising: a first voltage source for applying a first voltage to the switching elements when charge is accumulated in the storage capacitors and the gate-electrode capacitors and a second voltage source for applying a second voltage to the switching elements so as to turn on the switching elements when the charges accumulated in the storage capacitors and the gate-electrode capacitors are read, the second voltage having a different voltage value than the first voltage or making obvious a method for inspecting an array substrate having gate lines, data lines that cross the gate lines, switching elements where the gate and data lines cross, pixel electrodes connected to the switching elements, storage capacitors formed by storage capacitor lines facing part of each pixel electrode and gate-electrode capacitors formed between the gate lines and the pixel electrodes comprising the steps of: applying a first voltage to the switching elements when charge is accumulated in the storage capacitors and the gate-electrode capacitors and applying a second voltage to the switching elements so as to turn on the switching elements when the charges accumulated in the storage capacitors and the gateApplication/Control Number: 10/629,130 Page 3

Art Unit: 2829

electrode capacitors are read, the second voltage having a different voltage value than the first voltage.

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Suzuki et al, Ueda et al and Yamazaki et al are cited to show prior art apparatus and methods for inspecting array substrates when voltages are applied and capacitors charged with values produced to determine if damage has occurred.

Claims 1-12 are allowed.

Any inquiry concerning this communication should be directed to Ernest F. Karlsen at telephone number 571-272-1961.

Ernest F. Karlsen

July 12, 2004

ERNEST KARLSEN PRIMARY EXAMINER